

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Yin-Chun Huang et al.

Serial No. 10/726,534 Examiner: Brian J. Sines

Confirmation No. 5944 Group Art Unit: 1743

Filed: December 4, 2003

For: CHIP WITH MEASURING RELIABILITY AND A METHOD
THEREOF

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT

Responsive to the Office Action, Paper No. 20070330, mailed April 3, 2007, please amend the application as follows.

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 3 of this paper.

Remarks begin on page 7 of this paper.